SN54HCT541, SN74HCT541 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS306A - JANUARY 1996 - REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- High-Current 3-State Outputs Interface Directly With System Bus or Can Drive up to 15 LSTTL Loads
- Data Flow-Through Pinout (All Inputs on Opposite Side From Outputs)
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These octal buffers and line drivers are designed to have the performance of the popular 'HC240 series and to offer a pinout with inputs and outputs on opposite sides of the package. This arrangement greatly facilitates printed circuit board layout.

The 3-state control gate is a 2-input NOR. If either output-enable ($\overline{OE1}$ or $\overline{OE2}$) input is high, all eight outputs are in the high-impedance state. The 'HCT541 provide true data at the outputs.

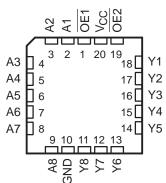
The SN54HCT541 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74HCT541 is characterized for operation from -40° C to 85°C.

SN54HCT541 J OR W PACKAGE SN74HCT541 DW OR N PACKAGE (TOP VIEW)										
		20	Vcc							
A1 [2	19	OE2							
A2 [3	18	Y1							
A3 [4	17	Y2							
A4 [5	16	Y3							
A5 [6	15	Y4							
A6 [7	14	Y5							
A7 [8	13	Y6							
A8 [9	12	Y7							

SN54HCT541 . . . FK PACKAGE (TOP VIEW)

11 **1** Y8

GND 1 10



FUNCTION TABLE (each buffer/driver)

	INPUTS	OUTPUT	
OE1	OE2	А	Y
L	L	L	L
L	L	Н	н
Н	Х	Х	Z
Х	Н	Х	Z



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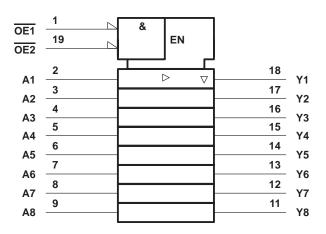
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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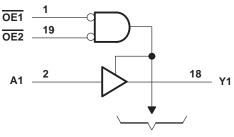
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range[‡]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{stg}	. −65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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recommended operating conditions

			SN54HCT541 SN74HCT541			41	UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	$V_{CC} = 4.5 V \text{ to } 5.5 V$	2			2			V
VIL	Low-level input voltage	$V_{CC} = 4.5 V \text{ to } 5.5 V$	0		0.8	0		0.8	V
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
tt	Input transition (rise and fall) time		0		500	0		500	ns
Т _А	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V_{CC} $T_A = 25^{\circ}C$ SN54HCT54		CT541	SN74H	CT541	UNIT			
PARAIWIETER	TEST CO	NDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vau	$\lambda = \lambda + \sigma \lambda$	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
Voh	$V_{I} = V_{IH} \text{ or } V_{IL}$	I _{OH} =6 mA	4.5 V	3.98	4.3		3.7		3.84		v
Vai		I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	v
VOL	$V_{I} = V_{IH} \text{ or } V_{IL}$	I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	v
li li	VI = VCC or 0		5.5 V		±0.1	±100		±1000		±1000	nA
I _{OZ}	$V_{O} = V_{CC} \text{ or } 0,$	$V_I = V_{IH} \text{ or } V_{IL}$	5.5 V		±0.01	±0.5		±10		±5	μA
ICC	$V_I = V_{CC} \text{ or } 0,$	IO = 0	5.5 V			8		160		80	μΑ
∆ICC‡	One input at 0.5 V of Other inputs at 0 or		5.5 V		1.4	2.4		3		2.9	mA
Ci			4.5 V to 5.5 V		3	10		10		10	pF

[†] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	то		Τį	λ = 25°C	;	SN54H	CT541	SN74H	CT541	UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
	А	Y	4.5 V		13	23		34		29	200	
^t pd	A	Ŷ	5.5 V		12	21		31		26	ns	
	ŌĒ	Y	4.5 V		21	30		45		38	ns	
ten			ľ	5.5 V		19	27		41		34	115
*	t _{dis} DE	Y	4.5 V		19	30		45		38	200	
ldis			5.5 V		18	27		41		34	ns	
		× ×	4.5 V		8	12		18		15		
t		Y	5.5 V		7	11		16		14	ns	



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switching characteristics over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ом то		Τį	λ = 25°C	;	SN54H	CT541	SN74H	CT541	UNIT													
FARAMETER	(INPUT)	(OUTPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT												
÷ .	tod A Y	4.5 V		20	33		49		42	ns														
^t pd	A	I	I	I	I		1	I	I	1		I	I	I	ľ	5	5.5 V	19	30		45		38	115
		×	4.5 V		26	40		60		50														
ten	OE	T	5.5 V		25	36		54		45	ns													
		Y	4.5 V		17	42		63		53														
tt			5.5 V		14	38		57		48	ns													

operating characteristics, $T_A = 25^{\circ}C$

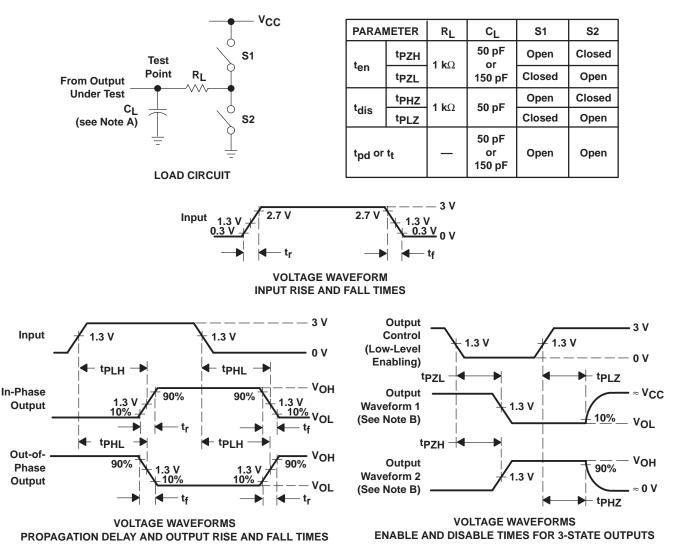
	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance per buffer/driver	No load	35	pF



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PARAMETER MEASUREMENT INFORMATION



- NOTES: A. CL includes probe and test-fixture capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns, t_f = 6 ns.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tpLz and tpHz are the same as tdis.
 - F. tp71 and tp7H are the same as ten.
 - G. tPLH and tPHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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